Application/Control No. Applicant(s)/Patent Under Reexamination 10/712,788 DELMULLE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Yuwen Pan 2618 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY * US-2001/0029166 10-2001 Rune et al. 455/41 Α * 02-2006 455/41.2 US-6,999,721 Ollis et al. В US-С US-D US-Ε US-F US-G US-Н USı US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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